

JAP20 Res'd PCT/PCT 17 FEB 2006
SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286321US0PCT	SERIAL NO. 68582 New U.S. PCT Application Based on PCT/JP04/11856		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Takashi KIKUKAWA, et al.					
		FILING DATE Herewith	GROUP				
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO	2004-220687	08/05/04	JP	YES	NO	
	AP	2004-39177	02/05/04	JP		NO	
	AQ	2004-087073	03/18/04	JP (with English abstract)		NO	
	AR						
	AS						
	AT						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AU	FUJI Hiroshi et al., "A Near-Field Recording and Readout Technology Using a Metallic Probe in an Optical Disk", Japanese Journal of Applied Physics, Vol. 39, Part 1, No. 2B, Pages 980 - 981, 2000.					
	AV	KIKUKAWA T. et al., "Rigid bubble pit formation and huge signal enhancement in super-resolution near-field structure disk with platinum-oxide layer", Applied Physics Letters, Vol. 81, No. 25, Pages 4697 - 4699, 2002.					
	AW	OKIKUKAWA T. et al., "Basic properties of Super-RENS disc with platinum oxide as a mask layer TDK", Vol. 63, page 1005, 2002.					
	AX	KIM Jooho et al., "Super-resolution by elliptical bubble formation with PtO _x and AgInSbTe layers", Applied Physics Letters, Vol. 83, No. 9, Pages 1701-1703, 2003.					
	AY	KIM Jooho et al., "Signal Characteristics of Super-RENS Disk at Blue Laser System, Technical Digest of International Symposium on Optical Memory, Pages 264 - 265, 2003.					
	AZ	KIM Jooho et al., "Random Pattern Signal Characteristics of Super-RENS Disk at Blue Laser System", Technical Digest of Optical Data Storage Topical Meeting, Pages 273 - 275, 2004.					
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner						Date Considered	1/4/08
<p>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286321US0PCT		SERIAL NO. 10/568,582	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Takashi KIKUKAWA, et al.					
		FILING DATE February 17, 2006		GROUP 2884			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
<i>mr</i>	AO	CN 1672202 A	9-21-2005	China (with English Abstract)	YES	NO	X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Murphy</i>		Date Considered <i>1/4/07</i>					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

		Docket No.: 286321US0PCT	Serial No.: 10/568,582		
LIST OF RELATED CASES CITED BY APPLICANT UNDER 37 CFR 1.56		Inventor: Takashi KIKUKAWA, et al.			
		Filing Date: February 17, 2006	Group:		
<u>LIST OF RELATED CASES</u>					
Examiner Initial	<u>Docket No.</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent App. Publication No.</u>	<u>Inventor or Applicant</u>
	286321US0PCT*	10/568,582	02/17/06		KIKUKAWA, et al.
	286323US0PCT	10/568,586	02/17/06		KIKUKAWA, et al.
	287042US2PCT	10/570,659	03/06/06		KIKUKAWA, et al.
	285143US0	11/337,611	01/24/06		KOBAYASHI, et al.
	284873US2PCT	10/565,679	01/24/06		FUKUZAWA, et al.
Examiner 			Date Considered		
<p>*Present Application; listed for information NFO/sbs/kch</p>					